

**AMENDMENTS TO THE ABSTRACT:**

Delete the current Abstract and replace therewith the attached substitute Abstract.

**ABSTRACT OF THE DISCLOSURE**

~~To prevent deformation of a component member such as a contactor unit to thereby perform a test under a satisfactory continuity condition.~~

A probe card ~~of the invention comprises~~ including a substrate body [[100]], a contactor unit [[300]] provided below the substrate body [[100]] for establishing an electrical contact with the subject to be tested as well as for establishing an electrical contact with the substrate body [[100]], a supporting ~~means 400~~ device for supporting the contactor unit [[300]] from below with elastic force and parallelism adjusting screws [[500]] that come in contact with the contactor unit [[300]] from above in a vertical direction for ~~adjusting a parallelism of the contactor unit 300~~ adjusting a degree of parallelism of the contactor unit. In particular, the supporting ~~means 400~~ device is configured to include a coil spring [[420]] interposed toward a vertical direction between a flange section [[411]] provided at the inside section of the support member [[410]] arranged below the substrate body [[100]] and a flange section [[321]] provided at the outside section of the contactor unit [[300]].